Power MOSFET

40 V, 0.67 m Ω , 420 A, Single N-Channel

Features

- Small Footprint (8x8 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- Power 88 Package, Industry Standard
- AEC-Q101 Qualified and PPAP Capable
- Wettable Flank Plated Option for Enhanced Optical Inspection
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

| Parameter | | | Symbol | Value | Unit |
|--|------------|----------------------------|-----------------------------------|-----------------|------|
| Drain-to-Source Voltage | | | V_{DSS} | 40 | V |
| Gate-to-Source Voltage | | | V_{GS} | ±20 | V |
| Continuous Drain | | | 420 | Α | |
| Current R _{0JC} (Notes 1, 3) | Steady | T _C = 100°C | | 297 | |
| Power Dissipation | State | T _C = 25°C | P_{D} | 205 | W |
| R _{θJC} (Note 1) | | T _C = 100°C | | 103 | |
| Continuous Drain | | T _A = 25°C | I _D | 65 | Α |
| Current R _{0JA} (Notes 1, 2, 3) | Steady | T _A = 100°C | | 46 | |
| Power Dissipation | State | T _A = 25°C | P_{D} | 4.9 | W |
| R _{θJA} (Notes 1, 2) | | T _A = 100°C | | 2.5 | |
| Pulsed Drain Current | $T_A = 25$ | °C, t _p = 10 μs | I _{DM} | 900 | Α |
| Operating Junction and Storage Temperature Range | | | T _J , T _{stg} | -55 to + 175 | °C |
| Source Current (Body Diode) | | | Is | 171 | Α |
| Single Pulse Drain-to-Source Avalanche Energy (I _{L(pk)} = 40 A) | | | E _{AS} | 1446 | mJ |
| Lead Temperature for Soldering Purposes (1/8" from case for 10 s) | | TL | 260 | °C | |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

| Parameter | Symbol | Value | Unit |
|---|-----------------|-------|------|
| Junction-to-Case - Steady State | $R_{\theta JC}$ | 0.73 | °C/W |
| Junction-to-Ambient - Steady State (Note 2) | $R_{\theta JA}$ | 30.4 | |

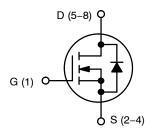
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



ON Semiconductor®

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| V _{(BR)DSS} | R _{DS(ON)} MAX | I _D MAX |
|----------------------|-------------------------|--------------------|
| 40 V | 0.67 m Ω @ 10 V | 420 A |



N-CHANNEL MOSFET



DFNW8 TX SUFFIX CASE 507AP

MARKING DIAGRAM



XXX = Device Code

(8 A-N characters max)

A = Assembly Location

WL = 2-digit Wafer Lot Code

Y = Year Code

WW = Work Week Code

ORDERING INFORMATION

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

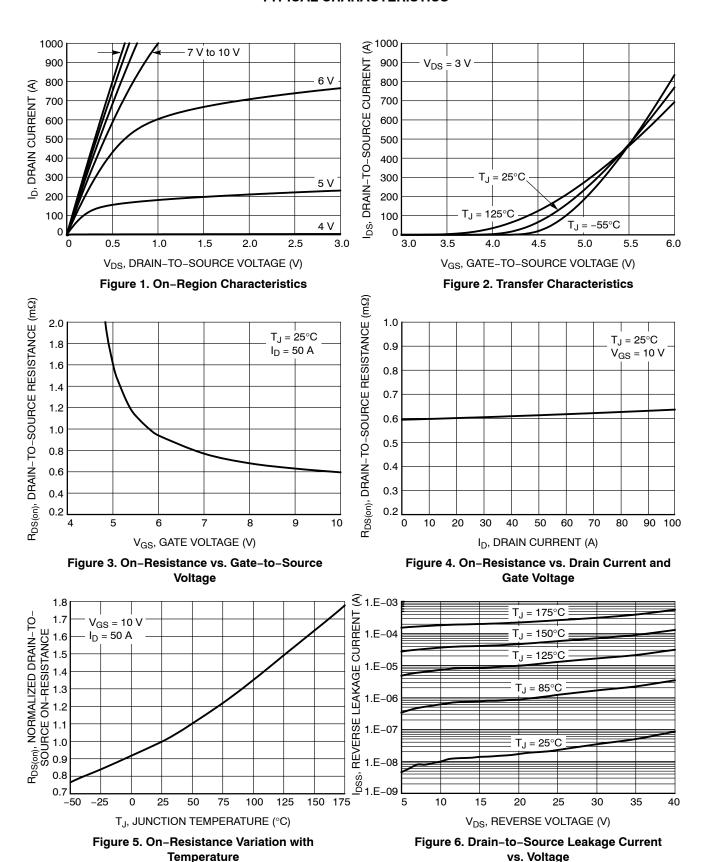
ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

| Parameter | Symbol | Test Condition | | Min | Тур | Max | Unit |
|--|--|--|------------------------|-----|------|------|-------|
| OFF CHARACTERISTICS | | | | • | | | |
| Drain-to-Source Breakdown Voltage | V _{(BR)DSS} | $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$ | | 40 | | | V |
| Drain-to-Source Breakdown Voltage Temperature Coefficient | V _{(BR)DSS} / T _J | | | | 20 | | mV/°C |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{GS} = 0 V, T _J = 25 °C | | | | 10 | |
| | | V _{DS} = 40 V | T _J = 125°C | | | 250 | μΑ |
| Gate-to-Source Leakage Current | I _{GSS} | V _{DS} = 0 V, V _{GS} = 20 V | | | | 100 | nA |
| ON CHARACTERISTICS (Note 4) | | | | | | | |
| Gate Threshold Voltage | V _{GS(TH)} | $V_{GS} = V_{DS}, I_D =$ | = 250 μA | 2.0 | | 4.0 | V |
| Threshold Temperature Coefficient | V _{GS(TH)} /T _J | | | | -8.5 | | mV/°C |
| Drain-to-Source On Resistance | R _{DS(on)} | V _{GS} = 10 V | I _D = 50 A | | 0.57 | 0.67 | mΩ |
| Forward Transconductance | 9 _{FS} | V _{DS} =5 V, I _D = 50 A | | | 200 | | S |
| CHARGES, CAPACITANCES & GATE RE | SISTANCE | | | | | | |
| Input Capacitance | C _{ISS} | V _{GS} = 0 V, f = 1 MHz, V _{DS} = 25 V | | | 9281 | | pF |
| Output Capacitance | C _{OSS} | | | | 5387 | | |
| Reverse Transfer Capacitance | C _{RSS} | | | | 176 | | |
| Total Gate Charge | Q _{G(TOT)} | V _{GS} = 10 V, V _{DS} = 20 V; I _D = 50 A | | | 140 | | |
| Threshold Gate Charge | Q _{G(TH)} | | | | 22.7 | |] _ |
| Gate-to-Source Charge | Q _{GS} | V _{GS} = 10 V, V _{DS} = 20 V; I _D = 50 A | | | 37 | | nC |
| Gate-to-Drain Charge | Q_{GD} | | | | 28.3 | | |
| Plateau Voltage | V _{GP} | | | | 4.28 | | V |
| SWITCHING CHARACTERISTICS (Note 5 | 5) | | | | | | |
| Turn-On Delay Time | t _{d(ON)} | V_{GS} = 10 V, V_{DS} = 20 V, I_{D} = 50 A, R_{G} = 2.5 Ω | | | 28.9 | | ns ns |
| Rise Time | t _r | | | | 18.1 | | |
| Turn-Off Delay Time | t _{d(OFF)} | | | | 61.0 | | |
| Fall Time | t _f | | | | 20.4 | | |
| DRAIN-SOURCE DIODE CHARACTERIS | TICS | | | | | | |
| Forward Diode Voltage | V_{SD} | V _{GS} = 0 V, | T _J = 25°C | | 0.8 | 1.2 | |
| | I _S = 50 A | T _J = 125°C | | 0.7 | | V | |
| Reverse Recovery Time | t _{RR} | $V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$ | | | 88.9 | | ns |
| Charge Time | t _a | | | | 57.9 | | |
| Discharge Time | t _b | | | | 31 | | |
| Reverse Recovery Charge | Q _{RR} | | | | 191 | | nC |

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.

^{5.} Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS

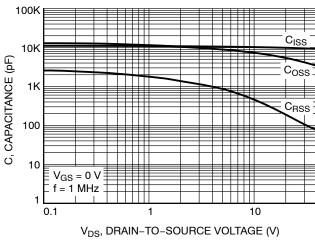


Figure 7. Capacitance Variation

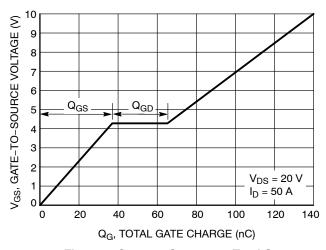


Figure 8. Gate-to-Source vs. Total Gate Charge

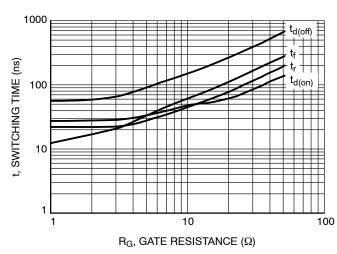


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

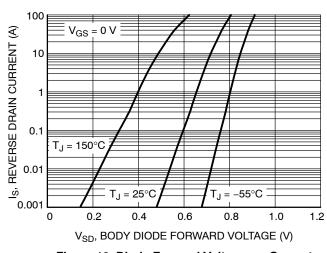


Figure 10. Diode Forward Voltage vs. Current

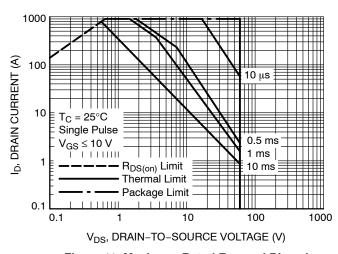


Figure 11. Maximum Rated Forward Biased Safe Operating Area

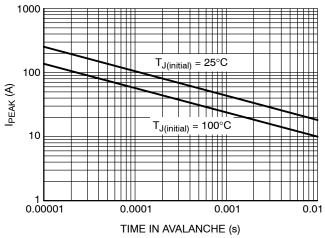


Figure 12. I_{PEAK} vs. Time in Avalanche

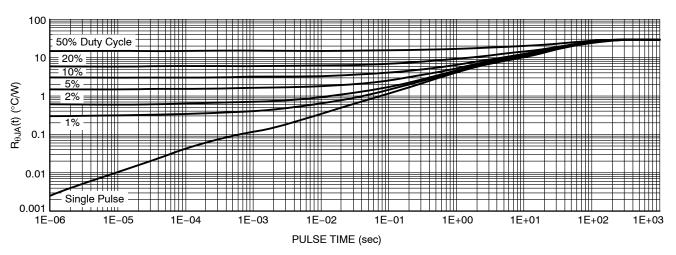


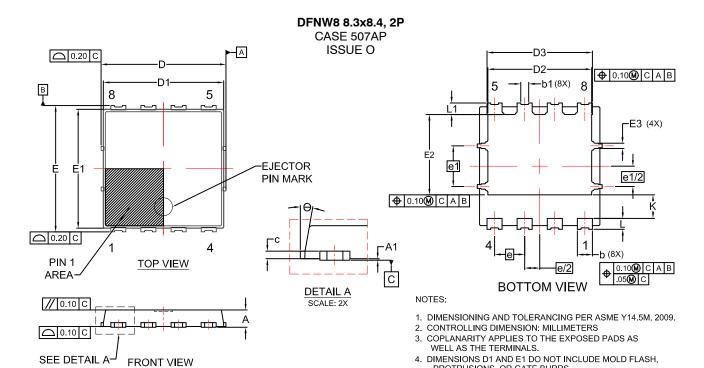
Figure 13. Thermal Characteristics

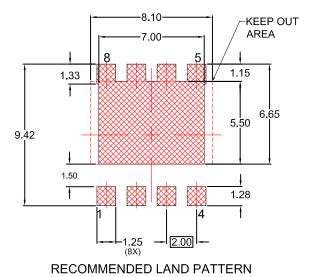
DEVICE ORDERING INFORMATION

| Device | Marking | Package | Shipping [†] |
|-----------------|---------|-----------------------|-----------------------|
| NVMTS0D7N04CTXG | 0D7N04C | POWER 88 (Pb–Free) | 3000 / Tape & Reel |

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS





MILLIMETERS DIM MIN. NOM. MAX. 1.00 1.20 1.10 Α A1 0.00 0.05 1.00 1.10 b 0.90 b1 0.43 0.53 0.63 0.23 0.28 0.33 D 8.20 8.30 8.40 D1 7.90 8.00 8.10 D2 6.80 6.90 7 00 D3 6.90 7.00 7.10 Е 8.30 8.50 8.40 E1 7.80 7.90 8.00 E2 5.34 5.44 5.24 E3 0.35 0.45 0.25 2.00 BSC 1.00 BSC e/2 e1 2.70 BSC 1.35 BSC e1/2 Κ 1.50 1.57 1.70 0.64 0.74 0.84 0.67 0.87 L1 0.77 θ 0° 12°

PROTRUSIONS, OR GATE BURRS. SEATING PLANE IS DEFINED BY THE TERMINALS.

"A1" IS DEFINED AS THE DISTANCE FROM THE SEATING
PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.

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